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Idriss Abid, Riad Kabouche, F Medjdoub, Sven Besendörfer, Elke Meissner, et al.. Remarkable Breakdown Voltage on AlN/AlGa<sub>N</sub>/AlN double heterostructure. 32nd International Symposium on Power Semiconductor Devices and ICs (ISPSD 2020), Sep 2020, Vienne, Austria. pp.310-312, 10.1109/ISPSD46842.2020.9170170 . hal-03044195

**HAL Id: hal-03044195**

**<https://hal.science/hal-03044195>**

Submitted on 7 Dec 2020

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# Remarkable Breakdown Voltage on AlN/AlGa<sub>0.5</sub>N/AlN double heterostructure

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**Abstract**— Ultra wide band gap (UWBG) materials such as AlN are part of a class of materials that have a larger band gap than conventional wide band gap (WBG) materials such as GaN, allowing higher operating voltages. In this work we present the fabrication and DC / high voltage characterizations of AlN/AlGa<sub>0.5</sub>N/AlN double heterostructure that are regrown by metalorganic chemical vapor deposition on AlN/sapphire. A buffer breakdown about 1100V with low leakage current for a spacing below 2μm is reported, which corresponds to a breakdown field about 6 MV/cm. Furthermore, transistors have been successfully fabricated on this heterostructure with low leakage current and low on-resistance. A breakdown voltage of 4.5kV with an off-state leakage current below 0.1 μA/mm have been indeed achieved. These results that AlGa<sub>0.5</sub>N-channel HEMTs are promising for high power, high temperature future applications.

**Keywords**— AlGa<sub>0.5</sub>N channel; High-Electron-Mobility Transistor (HEMT); Ultra-Wide Band Gap, AlN

## I. INTRODUCTION

GaN-based HEMTs and SiC power semiconductors are the material of choice for high power applications owing to their superior breakdown voltage (about 10 times) over their Si competitors. Today, the WBG-based electronics are maturing rapidly and have found large-scale market adoption in electric vehicles, power supplies, and photovoltaic (PV) inverters. However, ultra-wide band gap materials such as AlN (6.2 eV) and related Al-rich AlGa<sub>0.5</sub>N channel could allow for further improvement, especially in terms of voltage and temperature operations [1-7]. In addition, the use of an AlN back barrier [8-10] would enable to both increase the electron confinement in the transistor channel and enhance the thermal dissipation. It has already been demonstrated that for extremely high temperature electronics, the properties of Al-rich transistors are already showing favorable comparisons to conventional WBG materials [11]. Nevertheless, very high voltage operation is still plagued by the material quality and the ability to implement high Al content above 50% into the channel. The premise of voltage enhancement with AlGa<sub>0.5</sub>N channels needs validation.

In this work, we demonstrate, state-of-the-art 3-terminal breakdown voltage (BV) for AlGa<sub>0.5</sub>N channel HEMTs with multiple kilovolts.

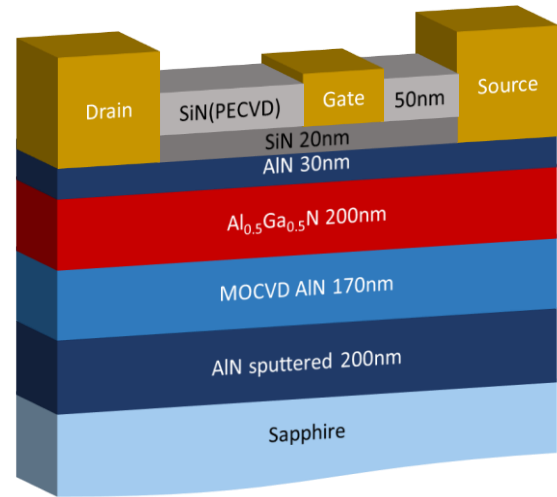


Fig. 1 : Schematic cross section of the AlN/AlGa<sub>0.5</sub>N/AlN HEMTs

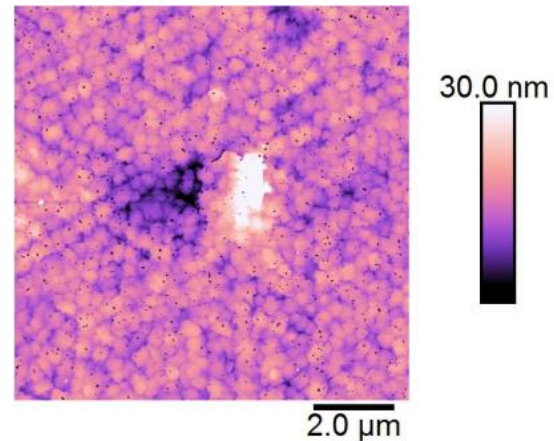


Fig. 2 : Schematic cross section of the AlN/AlGa<sub>0.5</sub>N/AlN HEMTs

## II. MATERIAL DESCRIPTION AND DEVICE FABRICATION

Fig. 1 shows a cross-sectional drawing of the fabricated AlGaIn channel HEMT. An AlN film with 200 nm thickness was grown on c-plane sapphire substrates by sputtering followed by annealing at 1700°C for 3h. Epitaxial layers, consisting of a 170-nm-thick AlN buffer, a 200-nm-thick  $\text{Al}_{0.5}\text{Ga}_{0.5}\text{N}$  channel, and a 30-nm-thick AlN barrier capped with a 20-nm thick SiN layer, were grown by metal-organic vapour phase epitaxy. All the layers were unintentionally doped. Fig. 2 shows an AFM image of the as grown structure, where the surface mirrors dislocation mediated island growth induced by screw type threading dislocations. This reflects the large room for improvement in terms of material quality. Source/drain ohmic contacts were obtained by etching the SiN cap as well as part of the AlN barrier with a deposition of a Ti/Al/Ni/Au metal stack annealed at 875°C.

As expected from previous work on AlGaIn channel, high contact resistances are observed. Si implantation or highly doped regrowth layer would be needed to achieve low contact resistances. Device isolation has been performed by mesa etching. A 2DEG charge density of  $1.9 \times 10^{13} \text{ cm}^{-2}$  with an electron mobility of  $145 \text{ cm}^2/\text{V.s}$  has been measured on Van der Pauw patterns. Ni/Au MIS gates were deposited on top of the SiN cap layer.

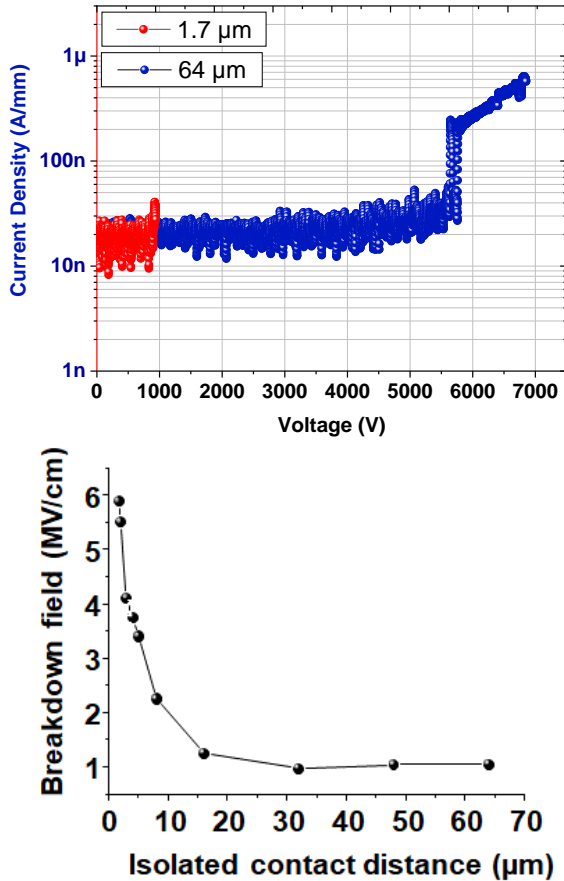


Fig. 3 : Buffer BV and breakdown field for various contact distances of AlN/AlGaIn/AlN HEMTs

## III. RESULTS AND DISCUSSION

Buffer BV on isolated contacts for various distances appears in Fig. 3. It can be noticed that the buffer breakdown reaches about 1000V with low leakage current for a spacing as low as 1.7  $\mu\text{m}$ , which corresponds to a remarkable breakdown field close to 6 MV/cm. For larger spacing, significant lateral buffer BV up to 7 kV has been measured, using a Keysight B1505A with N1268A Ultra High Voltage Expander. It can be pointed out that the BV drop for larger contact distances is mainly limited by the sapphire substrate, which has about 0.5 MV/cm breakdown strength.

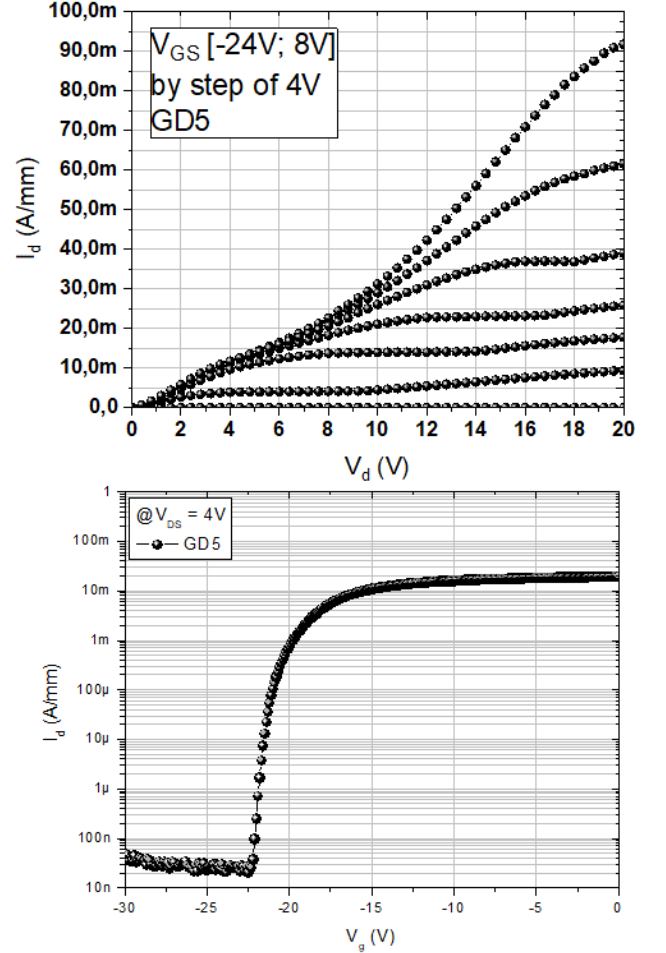


Fig. 4 : Output characteristics and transfer characteristics for a gate-drain distance of 5  $\mu\text{m}$  of AlN/AlGaIn/AlN HEMTs

DC characteristics show fully functional devices (Fig 4). Although the ohmic contacts are quite poor, a maximum current density above 90 mA/mm with an off-state leakage current around 20 nA/mm has been obtained on devices with gate width/length =  $50\mu\text{m}/1.5\mu\text{m}$  and gate-to-drain spacing ( $L_{GD}$ ) of 5  $\mu\text{m}$  (yielding an  $I_{ON}/I_{OFF}$  ratio close to  $10^6$ ). Strong pinch-off and no punch-through effects are observed owing to the efficient AlN back barrier. Low leakage current is obtained without the use of field plates confirming that tunneling mechanisms are not present in Al-rich transistors. In general, Al-rich transistors are less prone to gate leakage than

AlGaIn/GaN HEMTs. The corresponding specific on-resistance  $R_{ON}$  ranges from 5.5 to 9.5 m $\Omega$ .cm<sup>2</sup> for the various transistor designs. Finally, Fig 5 show the 3-terminal BV as a function of the transistor gate-drain distance measured at  $V_{GS} = -25$  V. Despite the rather high defect density, a record BV of 4500V with an off-state leakage current below 0.1  $\mu$ A/mm is achieved for AlGaIn-based channel HEMTs. It can be noticed that low gate-drain of 5  $\mu$ m yields a breakdown field of 3.5 MV/cm, which is well-beyond that of SiC and GaN devices.

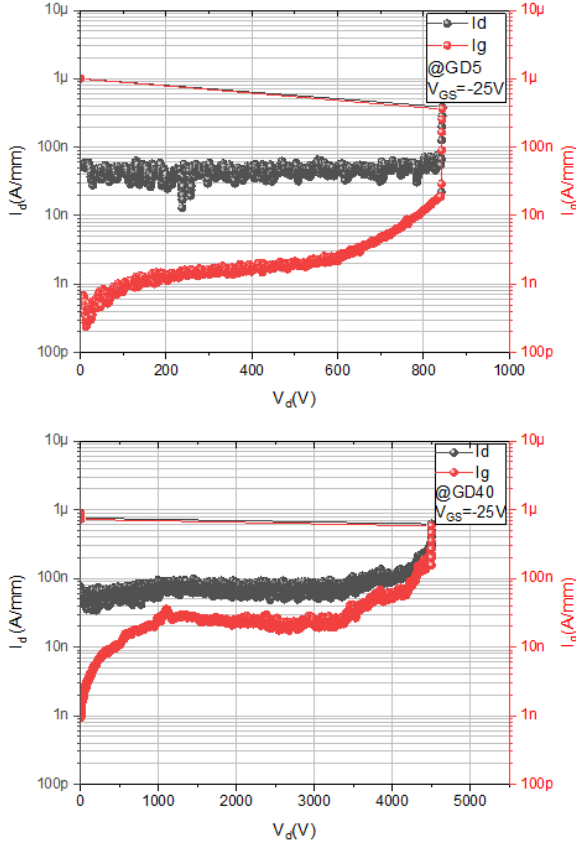


Fig. 5: 3-terminal off-state BV for various GD distances of AlN/AlGaIn/AlN HEMTs

#### IV. CONCLUSIONS

In summary, Al-rich AlGaIn channel combined with AlN material offers great potential as the material of choice for the next generation of transistors for power switching applications. We have shown the possibility to operate at high voltage using an AlN/AlGaIn/AlN heterostructure with 50% Al content into the channel. This resulted in an increase in the critical electric field as compared to more standard GaN HEMTs. Further study of the breakdown mechanisms may offer insight toward increasing breakdown fields in Al-rich transistors.

Although epitaxial growth efforts have mainly been conducted on sapphire substrates, AlN may be the long-term best

substrate for Al-rich transistors, in spite of its immaturity. Its advantages include a better thermal conductivity and a better crystalline quality due to near lattice-matched growth conditions for Al<sub>x</sub>Ga<sub>1-x</sub>N with large x.

#### ACKNOWLEDGMENT

This work is supported by the French RENATECH network and the French National grant ANR-17-CE05-00131 within the project called BREAKUP and the project InRel-NPower, which has received funding from the European Union's Horizon 2020 research and innovation programme under grant agreement No. 720527.

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